

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

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44500-00342

SERIAL NO.
10/658,984

Jahns et al.

FILING
September 10, 2003

GROUP
2857

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
dw	1.	5,658,423	08/19/97	ANGELL ET AL.	438	9	
↑	2.	5,864,773	01/26/99	BARNA ET AL.	702	85	
	3.	6,153,115	11/28/00	LE ET AL.	216	60	
	4.	6,192,826	02/27/01	SMITH, JR. ET AL.	118	723	
	5.	6,419,846	07/16/02	TOPRAC ET AL.	216	60	
	6.	6,442,445	08/27/02	BUNKOFSKE ET AL.	700	108	
	7.	6,521,080	02/18/03	BALASUBRAMHANYA	156	345.24	
	8.	2002/0104832	08/08/02	TANAKA ET AL.	219	121.41	
↓	9.	2002/0119668	08/29/02	BELL	438	707	
dw	10.	2003/0055523	03/20/03	BUNKOFSKE ET AL.	700	108	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

dw	A.	Infineon Technologies, "USING MULTI WAY PCA (MPCA) FOR ADVANCED MONITORING AND DIAGNOSIS FOR PLASMA PROCESSING BASED ON OPTICAL EMISSION SPECTROSCOPY" by Zimpel et al., SEMATECH AEC/APC Symposium XII, (Sept. 24-28, 2000)
dw	B.	Infineon Technologies, "SUPERVISION OF PLASMA PROCESSES USING MULTI-WAY PRINCIPAL COMPONENT ANALYSIS" by Knobloch et al, IVC-15 Int'l Symposium. (Oct. 02-06, 2000)

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

